Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/706,904	CHOI ET AL.
Examiner	Art Unit
Binh X. Tran	1765

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	SEARCHED					
Class	Subclass	Date	Examiner			
216	68	8/17/2005	ВТ			
216	71	8/17/2005	ВТ			
216	72	8/17/2005	ВТ			
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TNI	INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH)
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Search keywords and inventor's name using USPAT, USPG-PUB, JPO, EPO, DERWENT	8/17/2005	ВТ
216/67; 216/79 text search only	8/17/2005	ВТ
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